

Diodes Inc. Material Data Sheet

Rev: August 2008

Part Number: BAT54AW-p-F, BAT54CW-p-F, BAT54WS -p-F

Weight (mg): p=package designator

(HF Date Code Limited) See Data Sheet

Element	Material Group	Materials	CAS (if applicable)	Average mass homogeneous Materal(%)		Mass (mg)	ppm Homogeneous Material	ppm overall
Chip	Silicon w/Metal	Doped Silicon*	7440-21-3	100.00%	2.17	0.14	1000000	21703
Leadframe	Alloy 42	Fe	7439-89-6	57.65%	26.74	1.67	576500	154175
		Ni	7440-02-0	41.00%			410000	109647
		Mn	7439-96-5	0.60%			6000	1605
		Cr(not Cr 6+)	7440-47-3	0.10%			1000	267
		Со	7440-48-4	0.50%			5000	1337
		Si	7440-21-3	0.15%			1500	401
Leadframe Plating	Silver	Silver	7440-22-4	100.00%	1.01	0.06	1000000	10097
Bond Wire	Copper Wire	Cu	7440-50-8	100.00%	0.18	0.01	1000000	1846
Encapsulation	CEL-1702HF-9	SiO2	60676-86-0	87.30%	66.27	4.13	873000	578515
		Epoxy Resin	29690-82-2	5.00%			50000	33134
		Phenol Resin	26834-02-6	5.00%			50000	33134
		Aromatic poly-phosphate		2.50%			25000	16567
		C	1333-86-4	0.20%			2000	1325
Lead Plating Finish	Matte Tin	Tin	7440-31-5	100.00%	3.62	0.23	1000000	36246
				Total	100.00	6.23		1000000

Tolerance ±10%

This data is based on information provided by our suppliers. We believe it to be correct but do not routinely validate it by measurement. It is for guidance only and Diodes Inc. does not guarantee its absolute accuracy or completeness

This product or product family does not contain any of the following substances except as CURRENTLY exempted by ELV II and RoHS and reported above:

Asbestos

Antimony Compounds
Azo compounds
Cadmium and cadmium compounds
Certain Shortchain Chlorinated Paraffins

Chlorinated organic compounds Halogens

Hexavalent chromium compounds Lead and lead compounds

Mercury and mercury compounds

REACH SVHCs: Anthracene

4,4'- Diaminodiphenylmethane

Dibutyl phthalate
Cyclododecane
Cobalt dichloride
Diarsenic pentaoxide
Diarsenic trioxide
Sodium dichromate, dihydrate

5-tert-butyl-2,4,6-trinitro-m-xylene (musk xylene)

Ozone Depleting Substances - Class I (CFCs, HBFCs, etc.)

Perfluorooctane Sulphonate (PFOS) or related compounds

Ozone Depleting Substances - Class II (HCFCs)

Polychlorinated Naphthalenes ( > 3 chlorine atoms)

Tributyl Tin (TBT) and Triphenyl Tin (TPT)

Polychlorinated Biphenyls (PCBs)

Tributyl Tin Oxide (TBTO)

Radioactive Substances

Bis (2-ethyl(hexyl)phthalate) (DEHP) Hexabromocyclododecane (HBCDD)

Alkanes, C10-13, chloro (Short Chain Chlorinated Paraffins)

Polybrominated biphenyls (PBB) and Polybrominated diphenyl ethers (PBDE) including DecaBDE

Bis(tributyltin)oxide Lead hydrogen arsenate Triethyl arsenate Benzyl butyl phthalate

<sup>\*</sup> The Silicon Chip is doped at atomic levels with trace amounts of elements that may include Phosphorus, Boron, Arsenic, and other elements. Metalization may include Titanium, Nickel, Aluminum, Silver or Gold These substances are not reported where their concentration is less than the minimum reportable level per the guidelines specified in the Tables o EIA JIG-101, <u>Material Composition Declaration for Electronic Products</u>.